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N-channel TrenchMOS logic level FET Rev. 02 — 31 January 2011

Product data sheet

Product profile 1.

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant

1.3 Applications

- 12 V loads
- Automotive systems

1.4 Quick reference data

- Suitable for logic level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating
- General purpose power switching
- Motors, lamps and solenoids

Table 1.	Quick reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	30	V
I _D	drain current	$V_{GS} = 5 V; T_{mb} = 25 °C;$ see <u>Figure 1</u> ; see <u>Figure 3</u>	[1]	-	-	75	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see Figure 2		-	-	157	W
Static cha	racteristics						
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C		-	4.4	5	mΩ
		$V_{GS} = 5 V; I_D = 25 A;$ $T_j = 25 °C; see Figure 11;$ see Figure 12		-	5.9	7	mΩ



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Table 1. Quick reference data continued						
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 75 \text{ A}; V_{sup} \leq 30 V; \\ R_{GS} &= 50 \Omega; V_{GS} = 5 V; \\ T_{j(init)} &= 25 ^\circ\text{C}; \text{unclamped} \end{split} $	-	-	327	mJ
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$V_{GS} = 5 V; I_D = 25 A;$ $V_{DS} = 24 V; T_j = 25 °C;$ see <u>Figure 13</u>	-	13	-	nC

1 2 3 SOT78A (TO-220AB)

[1] Continuous current is limited by package.

2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		-
3	D	drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

3. Ordering information

Table 3. Ordering informati	ion
-----------------------------	-----

Type number	Package		
	Name	Description	Version
BUK9507-30B	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter			Min	Max	Unit
desire a suma suelte se					
-	, ,		-	30	V
drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	30	V
gate-source voltage			-15	15	V
drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 5 \text{ V}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 3}};$	<u>[1]</u>	-	108	A
	T_{mb} = 100 °C; V_{GS} = 5 V; see <u>Figure 1</u>	<u>[1]</u>	-	75	А
	T_{mb} = 25 °C; V_{GS} = 5 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	[2]	-	75	A
peak drain current	$T_{mb} = 25 \text{ °C}; \text{ pulsed}; t_p \le 10 \mu\text{s}; \text{ see } \frac{\text{Figure } 3}{10 \mu\text{s}}$		-	435	А
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	157	W
storage temperature			-55	175	°C
junction temperature			-55	175	°C
diode					
source current	T _{mb} = 25 °C	<u>[1]</u>	-	108	А
		[2]	-	75	А
peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^\circ C$		-	435	А
ggedness					
non-repetitive drain-source avalanche energy	I_D = 75 A; $V_{sup} \le 30$ V; $R_{GS} = 50$ Ω; $V_{GS} = 5$ V; $T_{j(init)} = 25$ °C; unclamped		-	327	mJ
	gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature diode source current peak source current ggedness non-repetitive drain-source	$\begin{array}{ccc} \text{drain-gate voltage} & \text{R}_{\text{GS}} = 20 \text{ k}\Omega \\ \\ \text{gate-source voltage} \\ \\ \text{drain current} & \begin{array}{c} T_{mb} = 25 \ ^{\circ}\text{C}; \ V_{\text{GS}} = 5 \ \text{V}; \ \text{see Figure 1}; \\ \text{see Figure 3} \\ \hline T_{mb} = 100 \ ^{\circ}\text{C}; \ V_{\text{GS}} = 5 \ \text{V}; \ \text{see Figure 1} \\ \hline T_{mb} = 25 \ ^{\circ}\text{C}; \ V_{\text{GS}} = 5 \ \text{V}; \ \text{see Figure 1}; \\ \text{see Figure 3} \\ \hline \text{peak drain current} & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{pulsed}; \ t_{p} \leq 10 \ \mu\text{s}; \ \text{see Figure 3} \\ \hline \text{total power dissipation} & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see Figure 2} \\ \hline \text{storage temperature} \\ \hline \text{junction temperature} \\ \hline \text{diode} \\ \hline \text{source current} & T_{mb} = 25 \ ^{\circ}\text{C} \\ \hline \text{peak source current} & T_{mb} = 25 \ ^{\circ}\text{C} \\ \hline \text{peak source current} & pulsed; \ t_{p} \leq 10 \ \mu\text{s}; \ T_{mb} = 25 \ ^{\circ}\text{C} \\ \hline \text{ggedness} \\ \hline \text{non-repetitive drain-source} & I_{D} = 75 \ \text{A}; \ V_{sup} \leq 30 \ \text{V}; \ \text{R}_{\text{GS}} = 50 \ \Omega; \ \text{V}_{\text{GS}} = 5 \ \text{V}; \end{array}$	$\begin{array}{c c} drain-gate \ voltage \\ \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	$\begin{array}{cccc} \mbox{drain-gate voltage} & R_{GS} = 20 \ k\Omega & & - & \\ \mbox{gate-source voltage} & & -15 \\ \mbox{drain current} & $T_{mb} = 25 \ ^{\circ}C; \ V_{GS} = 5 \ V; \ see \ Figure 1; & [1] & - & \\ & $r_{mb} = 100 \ ^{\circ}C; \ V_{GS} = 5 \ V; \ see \ Figure 1 & [1] & - & \\ & $T_{mb} = 25 \ ^{\circ}C; \ V_{GS} = 5 \ V; \ see \ Figure 1; & [2] & - & \\ & $r_{mb} = 25 \ ^{\circ}C; \ V_{GS} = 5 \ V; \ see \ Figure 3 & - & \\ & $total \ power \ dissipation & $T_{mb} = 25 \ ^{\circ}C; \ see \ Figure 2 & - & \\ & $storage \ temperature & $T_{mb} = 25 \ ^{\circ}C; \ see \ Figure 2 & - & \\ & $storage \ temperature & -55 \\ \\ \hline \mbox{diode} & $T_{mb} = 25 \ ^{\circ}C; \ see \ Figure 2 & - & \\ & $source \ current & $T_{mb} = 25 \ ^{\circ}C; \ see \ Figure 2 & - & \\ & $source \ current & $T_{mb} = 25 \ ^{\circ}C; \ see \ Figure 2 & - & \\ & $forage \ temperature & -55 \\ \hline \mbox{diode} & -55 \\ \hline \mbox{diod} & -55 \\ \hline \\mbox{diod} & -55 \\ \hline \mbox{diod} & -55 \\ \hline \\mbox{diod} & -55 \\ \hline \\mbox{diod} & -55 \\ \hline \mbox{diod} & -55 \\ \hline \\mbox{diod} & -55 \\ \hline \d$	$\begin{array}{cccc} drain-gate \ voltage & R_{GS} = 20 \ k\Omega & - & 30 \\ \texttt{gate-source voltage} & -15 & 15 \\ \texttt{drain current} & $T_{mb} = 25 \ ^\circ C; \ V_{GS} = 5 \ V; \ \texttt{see Figure 1}; & \texttt{[1]} & - & 108 \\ & \texttt{see Figure 3} & \texttt{T}_{mb} = 100 \ ^\circ C; \ V_{GS} = 5 \ V; \ \texttt{see Figure 1}; & \texttt{[1]} & - & 75 \\ \hline $T_{mb} = 25 \ ^\circ C; \ V_{GS} = 5 \ V; \ \texttt{see Figure 1}; & \texttt{[2]} & - & 75 \\ \hline $T_{mb} = 25 \ ^\circ C; \ V_{GS} = 5 \ V; \ \texttt{see Figure 3} & - & 435 \\ \hline $total \ power \ dissipation & $T_{mb} = 25 \ ^\circ C; \ \texttt{pulsed}; \ \texttt{t}_p \leq 10 \ \texttt{\mu}\texttt{s}; \ \texttt{see Figure 3} & - & 435 \\ \hline $total \ power \ dissipation & $T_{mb} = 25 \ ^\circ C; \ \texttt{see Figure 2} & - & 157 \\ \ \texttt{storage temperature} & $-55 \ 175 \\ \ \texttt{junction temperature} & $-55 \ 175 \\ \hline $diode & $-55 \ 175 \ diode & $-55 \ diode & $$

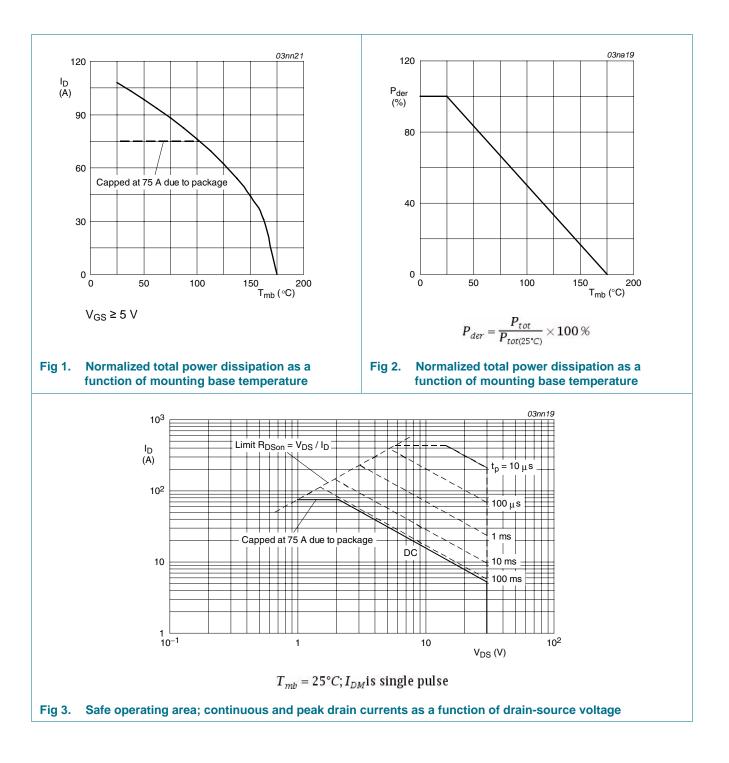
[1] Current is limited by power dissipation chip rating.

[2] Continuous current is limited by package.

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5. Thermal characteristics

Parameter	Conditions	Min	Тур	Max	Unit
thermal resistance from junction to mounting base	see Figure 4	-	-	0.95	K/W
thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W
	thermal resistance from junction to mounting base	thermal resistance from junction to mounting see Figure 4 base	thermal resistance from junction to mounting see Figure 4 - base	thermal resistance from junction to mounting see Figure 4 base	thermal resistance from junction to mounting see <u>Figure 4</u> 0.95 base

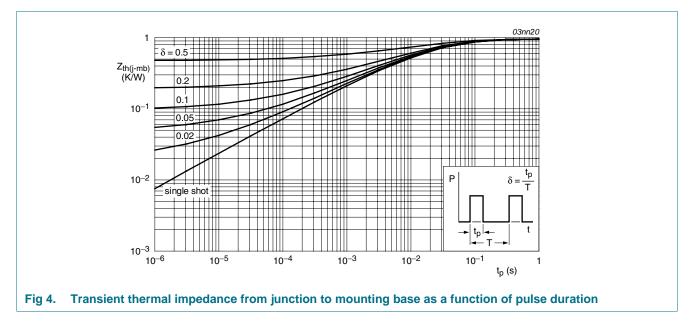


Table 5. Thermal characteristics

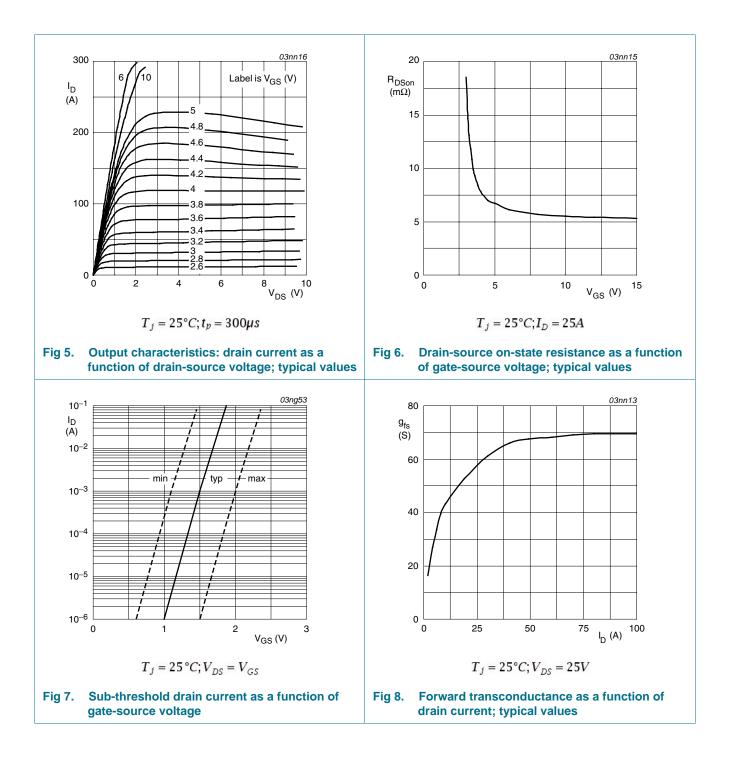
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6. Characteristics

Table 6.	Characteristics			-		
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
	aracteristics					
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	30	-	-	V
	-	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	27	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 10</u>	1.1	1.5	2	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 175 °C; see <u>Figure 10</u>	0.5	-	-	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 10</u>	-	-	2.3	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; \text{ V}_{GS} = 0 \text{ V}; \text{ T}_{j} = 175 \text{ °C}$	-	-	500	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μΑ
GSS	gate leakage current	$V_{GS} = 15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C	-	2	100	nA
R _{DSon}	drain-source on-state	$V_{GS} = 10 \text{ V}; \text{ I}_{D} = 25 \text{ A}; \text{ T}_{j} = 25 \text{ °C}$	-	4.4	5	mΩ
	resistance	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 11; see Figure 12	-	-	13.3	mΩ
		V _{GS} = 4.5 V; I _D = 25 A; T _j = 25 °C	-	-	9	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 11; see Figure 12	-	5.9	7	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V}; V_{GS} = 5 \text{ V};$	-	32	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 13</u>	-	7.6	-	nC
Q _{GD}	gate-drain charge		-	13	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 V$; $V_{DS} = 25 V$; f = 1 MHz; T _j = 25 °C; see <u>Figure 14</u>	-	2530	3373	pF
C _{oss}	output capacitance		-	635	762	pF
C _{rss}	reverse transfer capacitance		-	268	367	pF
d(on)	turn-on delay time	V_{DS} = 25 V; R_{L} = 1.2 Ω ; V_{GS} = 5 V;	-	30	-	ns
t _r	rise time	R _{G(ext)} = 10 Ω; T _j = 25 °C	-	135	-	ns
t _{d(off)}	turn-off delay time		-	99	-	ns
t _f	fall time		-	98	-	ns
L _D	internal drain inductance	from contact screw on mounting base to centre of die $; T_j = 25 \text{ °C}$	-	3.5	-	nH
		from drain lead 6 mm from package to centre of die ; $T_j = 25 \text{ °C}$	-	4.5	-	nH
-s	internal source inductance	from source lead 6 mm from package to source bond pad ; $T_j = 25 \text{ °C}$	-	7.5	-	nH
Source-d	rain diode					
V _{SD}	source-drain voltage	I _S = 25 A; V _{GS} = 0 V; T _j = 25 °C; see <u>Figure 15</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	I _S = 20 A; dI _S /dt = -100 A/μs;	-	52	-	ns
Q _r	recovered charge	V _{GS} = -10 V; V _{DS} = 25 V; T _j = 25 °C	-	35	-	nC

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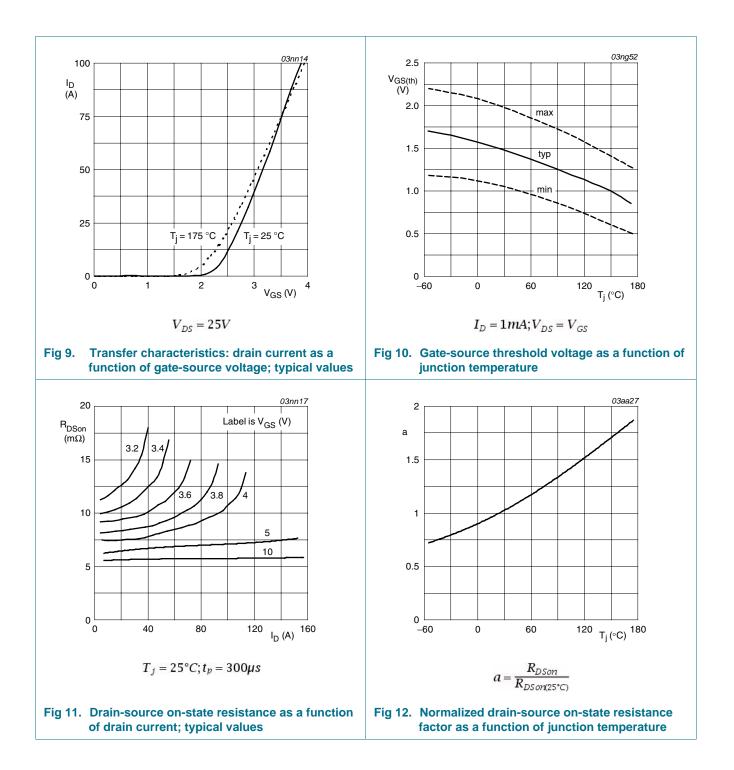


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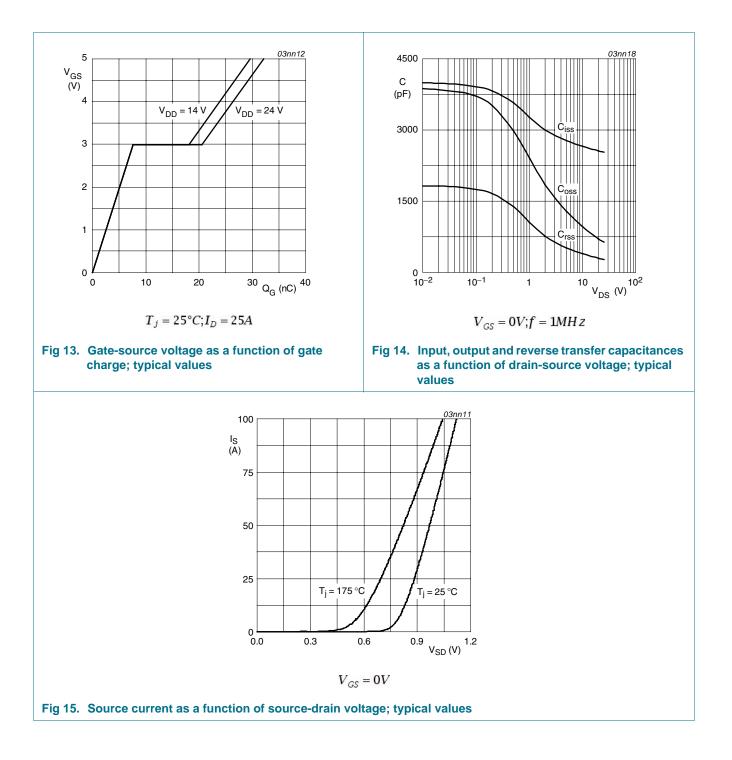
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7. Package outline

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							0 L			10 mm]						
	IONS (n A	A1	the origi b	nal dime b ₁	ensions) c	D	D ₁	E	е	L	L ₁ ⁽¹⁾	L ₂	р	q	Q	
	4.5	1.39	0.9	1.3	0.7	15.8	6.4	10.3		15.0	3.30	max. 3.0	3.8	3.0	2.6	-
mm	4.1	1.27	0.6	1.0	0.4	15.2	5.9	9.7	2.54	13.5	2.79	3.0	3.6	2.7	2.2	
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Fig 16. Package outline SOT78A (TO-220AB)

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8. Revision history

Table 7. Revision h	istory						
Document ID	Release date	Data sheet status	Change notice	Supersedes			
BUK9507-30B v.2	20110131	Product data sheet	-	BUK95_9607_30B v.1			
Modifications:	 The format of this of NXP Semicond 	data sheet has been rede uctors.	esigned to comply with th	e new identity guidelines			
	 Legal texts have been adapted to the new company name where appropriate. 						
	 Type number BUK 	(9507-30B separated from	n data sheet BUK95_960	7_30B v.1.			
BUK95_9607_30B v.1	20030425	Product data	-	-			

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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